In the claims:

Please amend claims 1, 4, 9-13 as follows.

1. (currently amended) A device for testing integrated circuits comprising:

a base;

a socket body held in the base for contacting a plurality of terminals from an integrated circuit;

a lid;

a hinge joining said lid to said base;

a locking mechanism allowing locking of said lid to said base;

a pressure plate retained within said lid;

two cam levers each mechanically linked to opposing sides of the lid for lowering said pressure plate from said lid to said socket when ~~an~~ the integrated circuit is placed within said socket.

2. (original) The device of claim 1, further including a sight groove on the base, said sight groove allowing a user to view the integrated circuit within said test socket.

3. (original) The device of claim 1, wherein said cam lever includes a pair of cam ratcheting levers with said cam ratcheting levers having ratchet like notches, with said cam ratcheting levers having elongate arms, said arms joined by a linking bar.

4. (currently amended) The device of claim 1, wherein said cam lever transforms ~~the~~ a rotational movement of said two cam ~~ratcheting~~ levers to a vertical movement of said pressure plate by the use of a cam means.

5. (original) The device of claim 1, further including a lock disposed to movably engage said cam levers, said lock preventing said cam levers from moving when said lock is engaged against said cam lever.

6. (original) The device of claim 5, wherein said lock is spring biased.

7. (original) The device of claim 1, wherein said pressure plate may include an open central area through which the integrated circuit may be viewed.

8. (original) The device of claim 1, wherein said socket body includes pogo pins.

9. (currently amended) A device for testing integrated circuits comprising:

a base;

a socket body within said base for contacting a plurality of terminals from an integrated circuit;

a lid;

a hinge joining said lid to said base;

a locking mechanism allowing locking of said lid to said base;

a pressure plate retained within said lid;

two ~~a cam ratcheting lever~~ means on opposing sides of the lid for incrementally lowering said pressure plate from said lid to said integrated circuit when [[a]] said integrated circuit is placed within said device;

a sight groove which extends through said base to allow for visual examination of the integrated circuit during test.

10. (currently amended) The device of claim 9, wherein said two means for incrementally lowering said pressure plate ~~cam ratcheting lever means~~ includes a pair of cam ratcheting levers with said cam ratcheting levers having ratchet like notches, with said cam ratcheting levers having elongate arms, said arms joined by a linking bar.

11. (currently amended) The device of claim 10, wherein said cam ratcheting levers transforms ~~the~~ a rotational movement of said cam ratcheting levers to a vertical movement of said pressure plate by the use of a cam means.

12. (currently amended) The device of claim 9, further including a lock disposed to movably engage said ~~cam ratcheting lever means~~ two means for incrementally lowering said pressure plate, said lock preventing said ~~cam ratcheting lever means~~ two means for incrementally lowering said pressure plate from moving when said lock is engaged against said ~~cam ratcheting lever means~~ two means for incrementally lowering said pressure plate.

13. (currently amended) The device of claim [[13]] 12, wherein said lock is spring biased.

14. (original) The device of claim 9, wherein said pressure plate includes an open central area through which said integrated circuit may be viewed.

15. (original) The device of claim 9, wherein said socket body includes pogo pins.